		Application/Control No.	Applicant(s)/Patent Under Reexamination
Notice of References Cited		09/985,768	BOATENG, KWAME OSEI
		Examiner	Art Unit	Page 1 of 1
		Vuthe Siek	2825	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
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FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Pomeranz et al., "On Static Compaction of Test Sequences for Synchronous Sequential Circuits," ACM, 1996, pages 1-6.
	V	Hamzaoglu et al., "Test Set Compaction Algorithms for Combinational Circuits*," ACM 1998, pages 283-289.
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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